

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Kimiaki TOSHIKIYO Group Art Unit : Not Yet Assigned
Appl. No. : 10/576,023 Examiner : Not Yet Assigned
 (U.S. National Stage of PCT/JP2004/018746)
I.A. Filed : April 17, 2006 Confirmation No. : Not Yet Assigned



: LIGHT-COLLECTING DEVICE AND SOLID-STATE IMAGING
APPARATUS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
U.S. Patent and Trademark Office
Customer Service Window, Mail Stop AMENDMENT
Randolph Building
401 Dulany Street
Alexandria, VA 22314

Sir:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and §§1.97-1.98, Applicants hereby submit the following documents:

- (1) Japanese Laid-Open Patent Publication No. 2001-196568, together with an English language Abstract of the same. Applicant notes that this document is cited on page 2 of the specification of the above-captioned application;
- (2) Japanese Laid-Open Patent Publication No. 2000-039503, together with an English language Abstract of the same. Applicant notes that this document is cited on page 2 of the specification of the above-captioned application;

- (3) Japanese Laid-Open Patent Publication No. HEI 5-251673, together with an English language Abstract of the same. Applicant notes that this document is cited on page 2 of the specification of the above-captioned application;
- (4) D. W. PRATHER, "Design and application of subwavelength diffractive lenses for integration with infrared photodetectors," Opt. Eng. 38(5), pages 870-878 (May 1999; Society of Photo-Optical Instrumentation Engineers);
- (5) U.S. Patent Application Publication No. 2006-0102827 to KASUGA et al., which was published on May 18, 2006; and
- (6) U.S. Patent Application No. 10/576,273.

The following documents are cited in an International Search Report (in Japanese and in English) with respect to PCT/JP2004/018746 that has been brought to the attention of the Examiner:

- (7) Japanese Laid-Open Patent Publication No. 2001-108812, together with an English language Abstract and an English language translation of a relevant part thereof.
- (8) Japanese Laid-Open Patent Publication No. 2001-318217, together with an English language Abstract and an English language translation of the relevant part thereof;
- (9) Japanese Laid-Open Patent Publication, No. HEI 7-113907, and patent family members U.S. Patent No. 5,742,433 to SHIONO et al., which issued on April 21, 1998; U.S. Patent No. 5,561,558 to SHIONO et al., which issued on October 1, 1996; and European Patent Publication No. 0649037;

- (10) Japanese Laid-Open Patent Publication No. 2003-229553, and patent family member U.S. Patent Application Publication No.2003-0168679 to NAKAI et al., which issued on September 11, 2003;
- (11) Japanese Laid-Open Patent Publication No. 2002-135796, together with an English language Abstract and an English language translation of the relevant part thereof; and
- (12) Japanese Laid-Open Patent Publication No. HEI 04-343471, together with an English language Abstract and an English language translation of a relevant part thereof.

The relevance of the documents cited in the International Search Report, as ascertained by the International Examiner, are set forth in the International Search Report.

Further to 37 C.F.R. §1.98 (a)(2)(ii), copies of the U.S. patents and patent application publications are not enclosed herewith. However, if any copy is needed, the Examiner is respectfully requested to contact the undersigned.

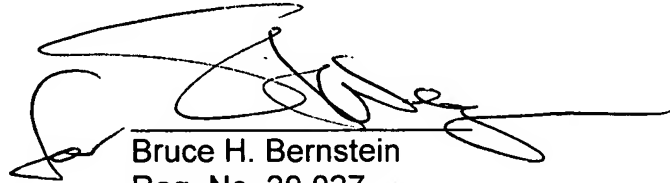
Applicant respectfully requests that the Examiner consider the above material and cite the same. Copies of the above-noted foreign documents and unpublished U.S. patent application are attached hereto, and all of the documents are listed on an attached PTO-1449 Form. The Examiner is requested to initial the appropriate space on the attached Form and to return a copy of the completed Form to Applicant with the next official communication in the present application.

P29771.A02

Applicant notes that an Office Action on the merits has not issued in the present application, and thus, no fee is believed necessary to ensure consideration of the submitted material.

Should the Examiner have any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

Respectfully submitted,
Kimiaki TOSHIKIYO

A handwritten signature in black ink, appearing to read "Bruce H. Bernstein", written over a horizontal line.

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FORM PTO-1449

U.S. Department of Commerce
Patent and Trademark OfficeAtty. Docket
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10/576,023INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

(Use several sheets if necessary)

Applicant
Kimiaki TOSHIKIYOI.A. Filing Date
April 17, 2006Group
Not Yet Assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2006/	0 1 0 2 8 2 7	05/18/06	KASUGA et al.			
		5 7 4 2 4 3 3	04/21/98	SHIONO et al.			
		5 5 6 1 5 5 8	10/01/96	SHIONO et al.			
	2003/	0 1 6 8 6 7 9	09/11/03	NAKAI et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
	2001	- 1 9 6 5 6 8	07/19/01	JAPAN				
	2000	- 0 3 9 5 0 3	02/08/00	JAPAN				
	5	- 2 5 1 6 7 3	09/28/93	JAPAN				
	2001	- 1 0 8 8 1 2	04/20/01	JAPAN			X	
	2001	- 3 1 8 2 1 7	11/16/01	JAPAN			X	
	7	- 1 1 3 9 0 7	05/02/95	JAPAN				
		0 6 4 9 0 3 7	04/19/95	E.P.O.				
	2003	- 2 2 9 5 5 3	08/15/03	JAPAN				
	2002	- 1 3 5 7 9 6	05/10/02	JAPAN			X	
	4	- 3 4 3 4 7 1	11/30/92	JAPAN			X	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

1	English Language Abstract JP 2001-196568.
2	English Language Abstract JP 2000-039503.
3	English Language Abstract JP 5-251673.
4	D. W. PRATHER, "Design and application of subwavelength diffractive lenses for integration with infrared photodetectors," Opt. Eng. 38(5), pages 870-878 (May 1999; Society of Photo-Optical Instrumentation Engineers).
5	U.S. Patent Application No. 10/576,273.
6	English Language Abstract of JP 2001-108812.
7	English Language Abstract of JP 2001-318217.
8	English Language Abstract of JP 2002-135796.
9	English Language Abstract of JP 4-343471.

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.